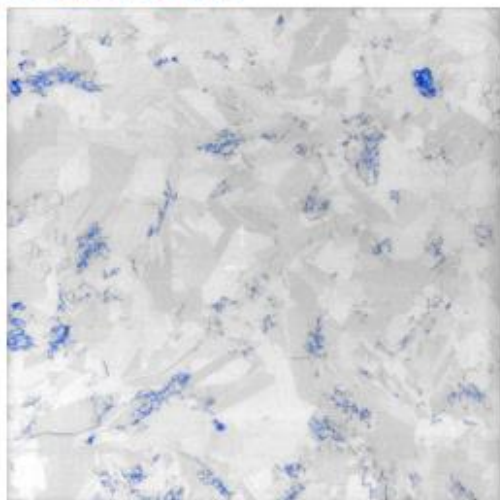


# Wafer Report



## PROCESSED IMAGE



## GENERAL



Measured: 27/06/2014 11:09 AM  
Operator: Jason  
Sample ID: 6823  
Batch: Multi Demo Batch

## RESULTS

Mean PL: 490  
Lifetime: 1.430  
Thickness: 180.617  
Resistivity: 1.473

## ANALYSIS

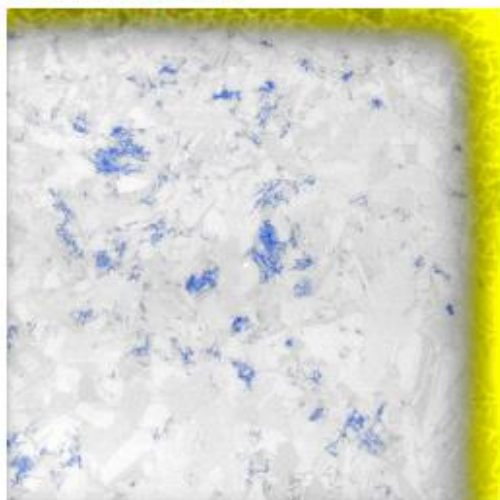
Recipe: multi default  
Bin: 1  
Grade: A1  
Q: 0.626

	IMPURE	0.00
	DEFECTS	2.89

# Wafer Report



## PROCESSED IMAGE



## GENERAL



Measured: 27/06/2014 10:33 AM  
Operator: Jason  
Sample ID: 8525  
Batch: Multi Demo Batch

## RESULTS

Mean PL: 667  
Lifetime: 1.437  
Thickness: 185.981  
Resistivity: 1.413

## ANALYSIS

Recipe: multi default  
Bin: 2  
Grade: B1  
Q: 0.875

	IMPURE	11.63
	DEFECTS	2.61